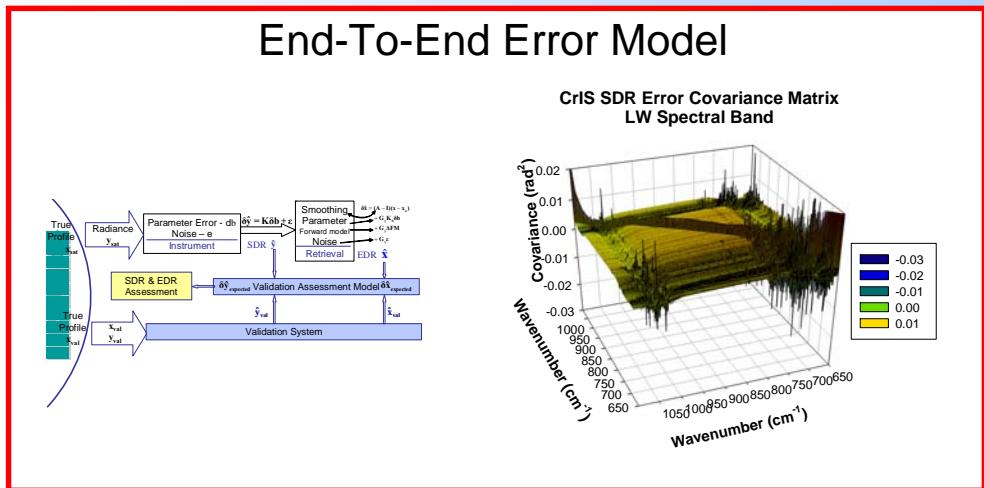


Pougatchev N. S., Bingham G. E., Esplin M. P., Cantwell G. W., Zavyalov V. V., and Ferguson D. A

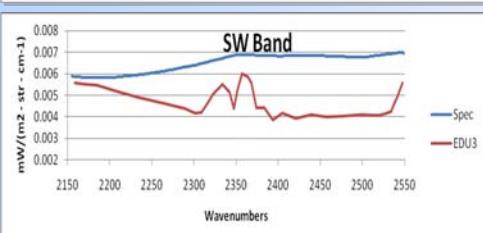
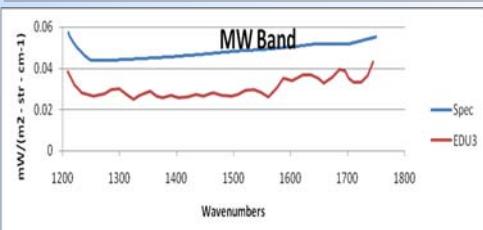
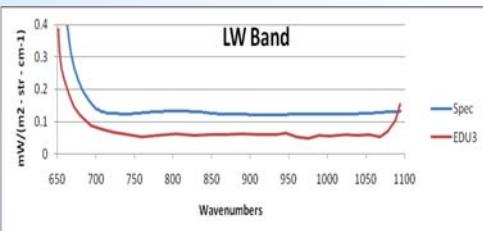
Understanding the sources of potential error in a CrIS sensor measurement is of critical importance. Although there are innumerable sources of error and uncertainty they can be grouped into the following categories:

- NEDN
- Radiometric Uncertainty
- Spectral Uncertainty



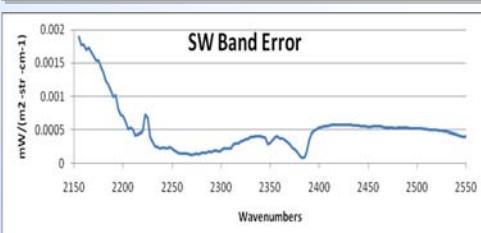
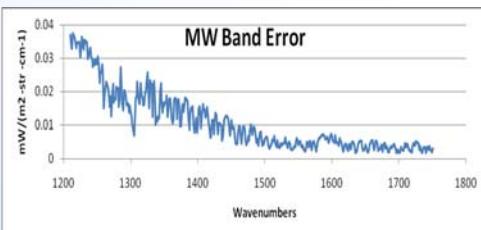
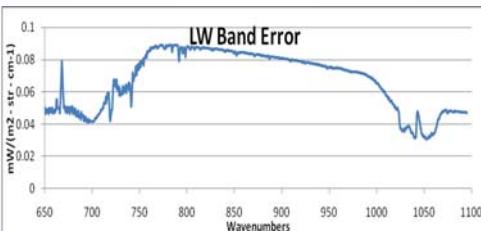
## NeDN

NEDN performance from the bench test results for the EDU3



## Radiometric Uncertainty

Radiance Error with a 0.08K ICT knowledge error



## Spectral Uncertainty

Error from a 10 ppm spectral shift

